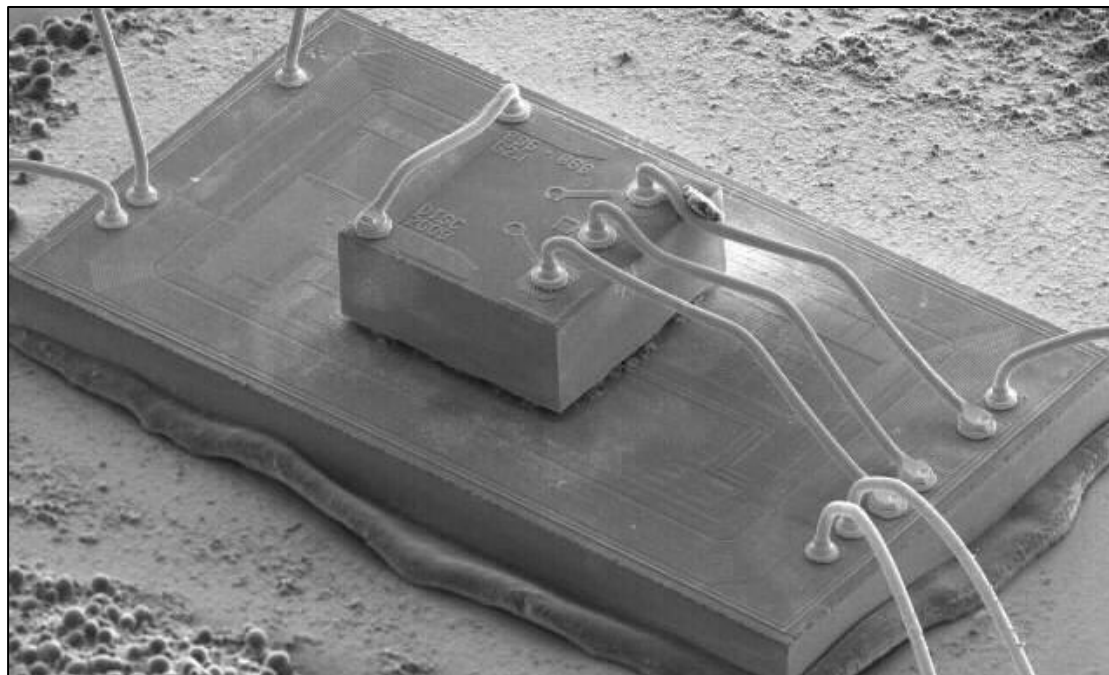


Reverse Costing analysis



Discera DSC8002 MEMS Oscillator

December 2010 - Version 1

Written by: Romain FRAUX

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Glossary

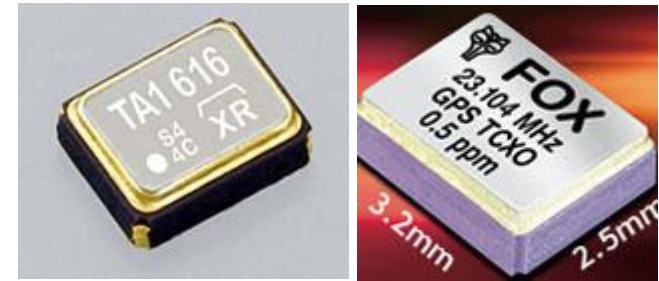
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• Players & technologies (Courtesy of Yole Développement)

3 major technologies are competing in the timing market:

• Quartz → the established technology

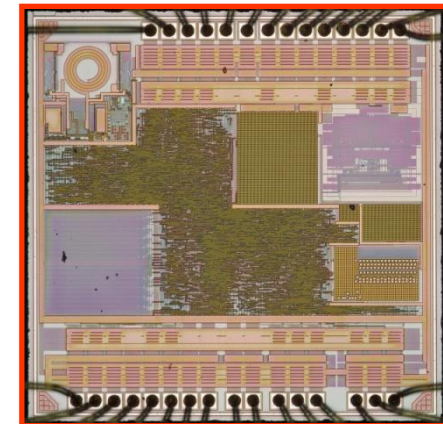
- Many players: Epson, NDK, TXC, Kyocera, IDT, ICT, Fox Electronics, KDS, Rakon
 - Analog part of the oscillator is done by semiconductor companies: Cypress, Asahi, NPC...
 - Semiconductor IC players are integrating those quartz components into clock generators: IDT, Maxim, Silicon Labs, Cypress...



Epson Toyocom / Fox Electronics oscillators

• CMOS → the low-end alternative

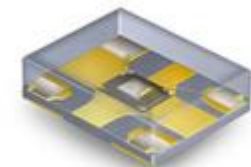
- LC circuits (inductor-capacitor) can be used as resonators
- Players Silicon Labs, Mobius microsystems (acquired by IDT in Jan. 2010), Linear Technology, Cypress...



Integration of Mobius Microsystems CMOS oscillator

• MEMS → the disruptive technology

- Players: SiTime, Discera, Silicon Clocks
 - In dev: Sand9, NXP, TXC, CSEM (with AlN piezo layer similar principle to the quartz principle)

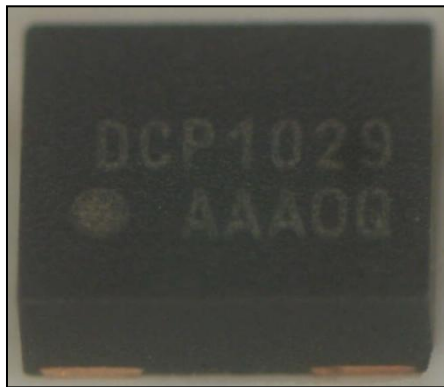


Ecliptek EMO MEMS oscillator

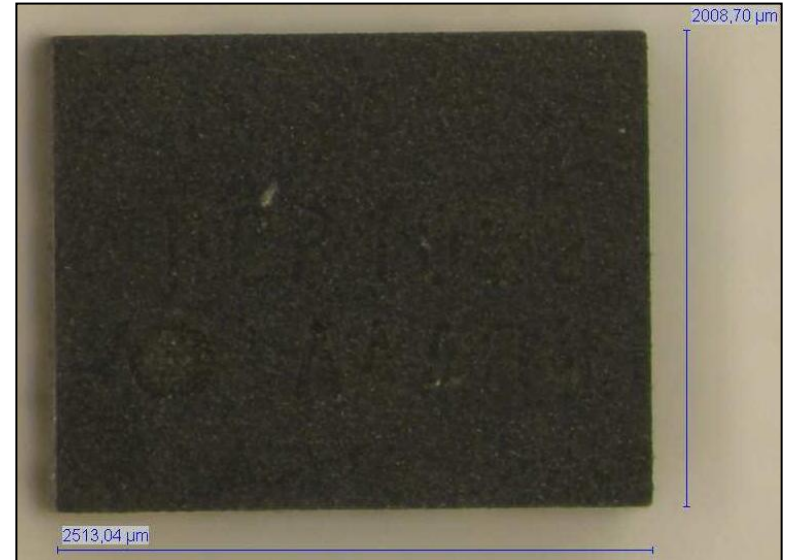
• Alternative technologies (niche markets): rubidom atomic oscillator, cesium...

DSC8002D

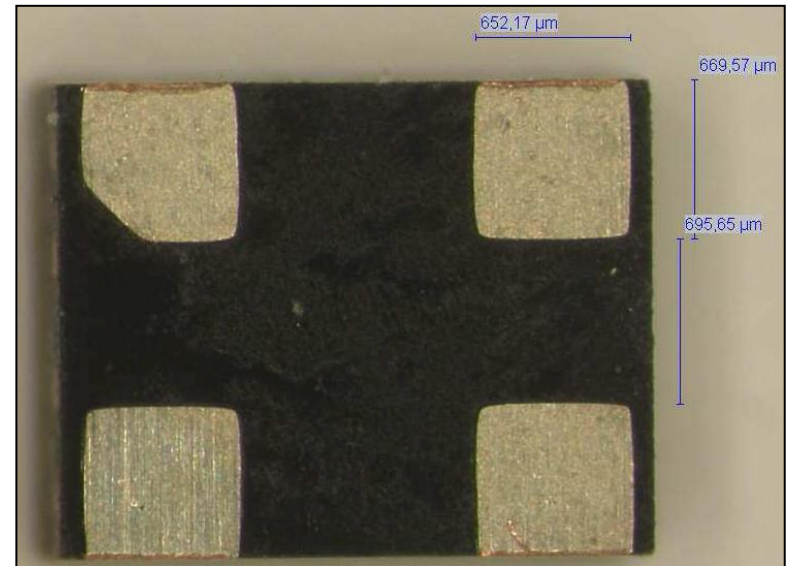
- Package type: 4-pin MLF
- Dimensions: 2.5mm x 2.0mm x 0.85mm
- Marking: DCP1029
AAAOQ



Package Marking



Package Top view

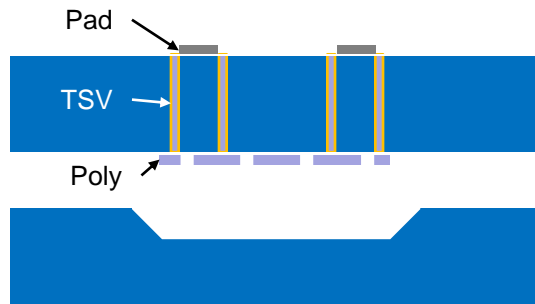


Package Back view



Package Side view

The schematic diagram below is based on the observations made during this study and detailed in the next slides.



1. The Resonator

- Connections via (TSV) etched by DRIE

- [Blurred text]
- [Blurred text]
- [Blurred text]
- [Blurred text]

2. The Cap

- Bulk micromachining

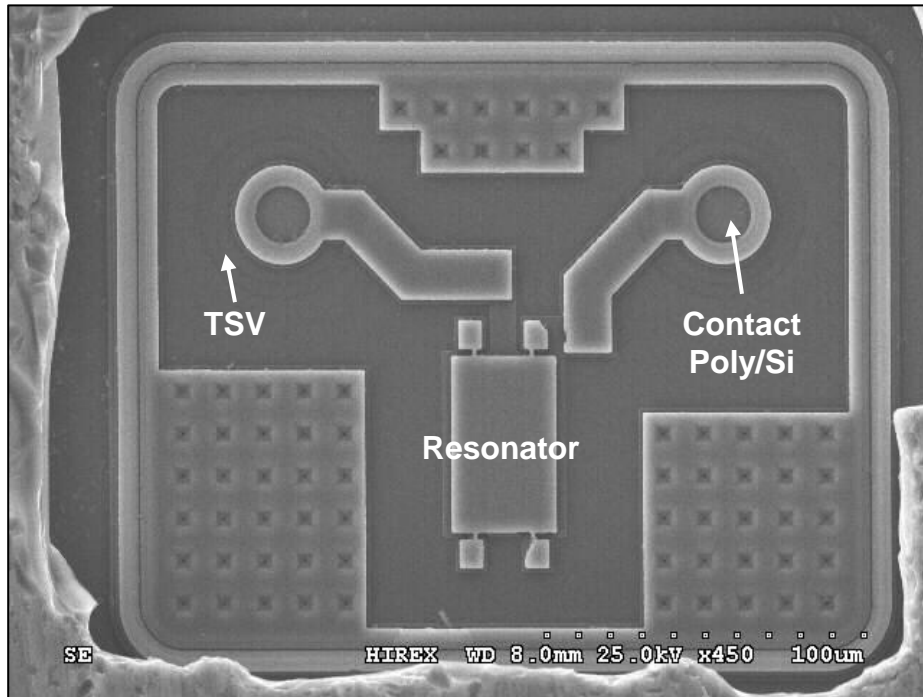
- [Blurred text]

3. The ASIC

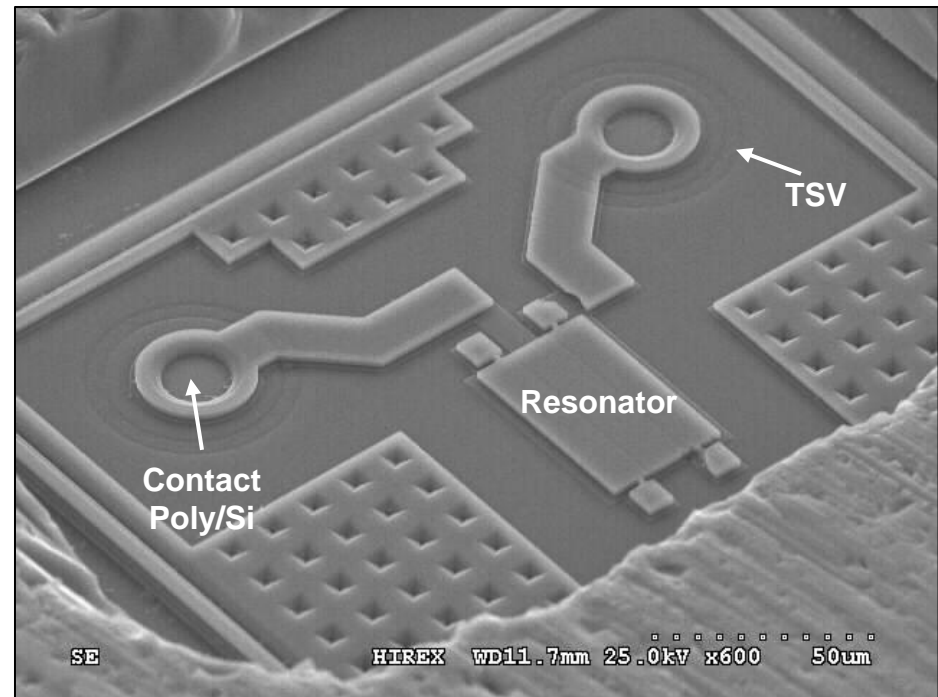
- CMOS 0.18 μ m 6M 1P

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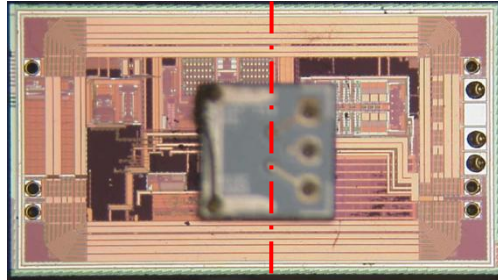
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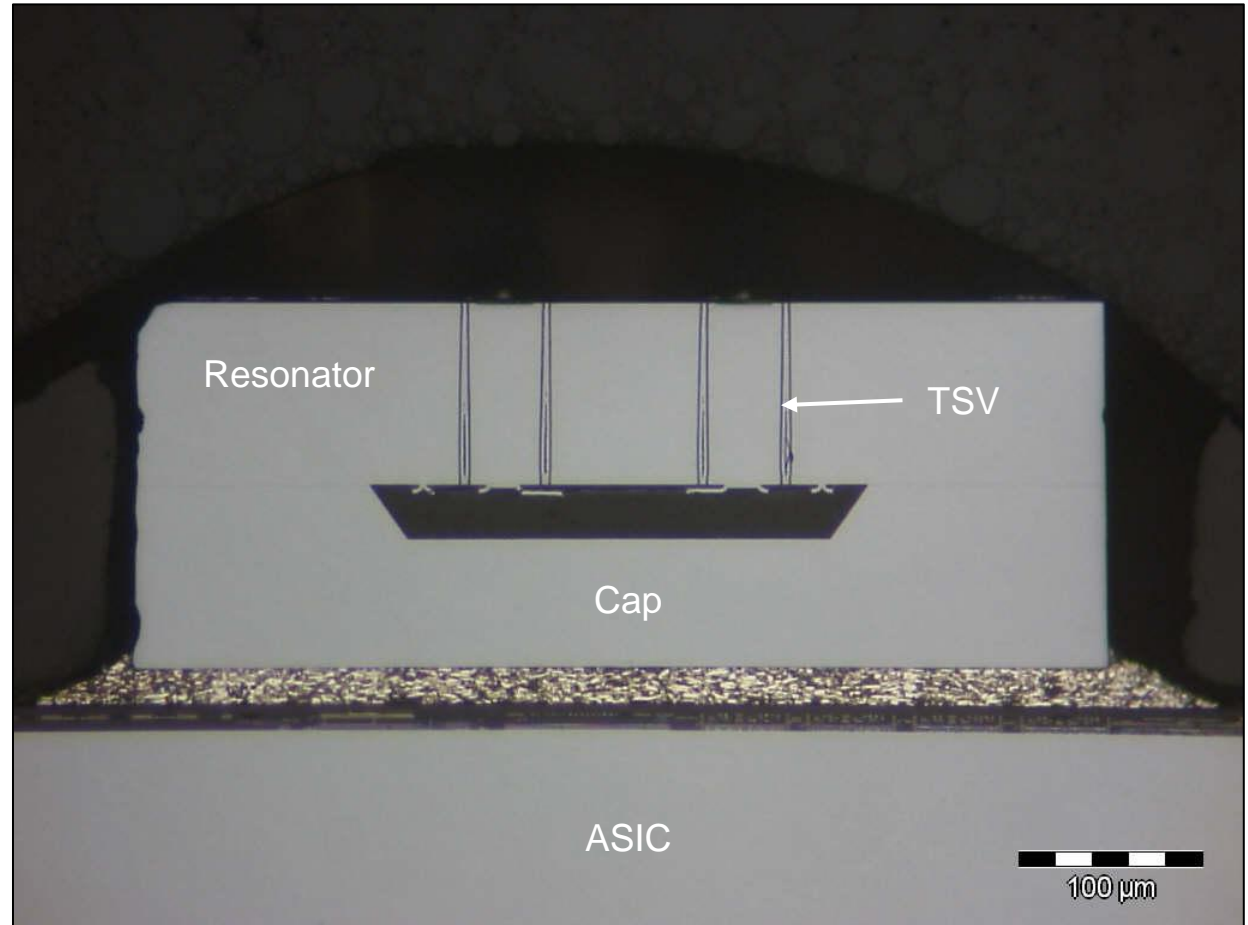
Resonator with connections – SEM View



Resonator with connections – Tilted SEM View



Cross-Sectional Plane BB'



AA' Cross Section Overview



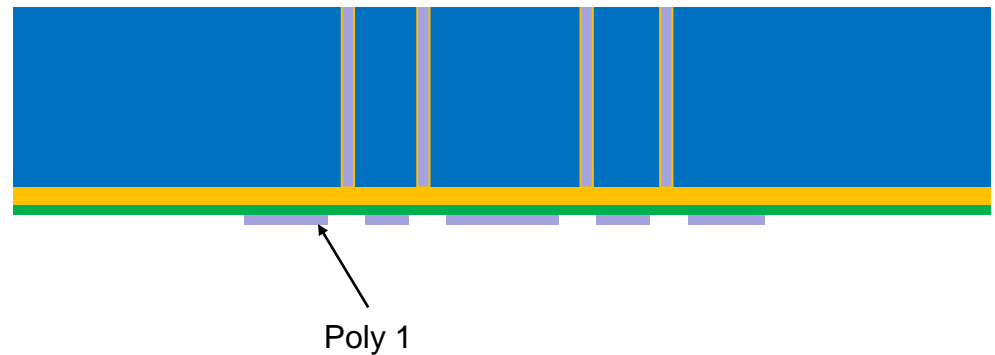
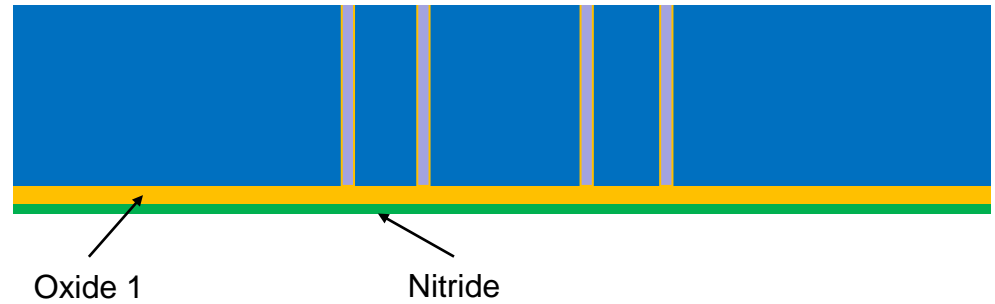
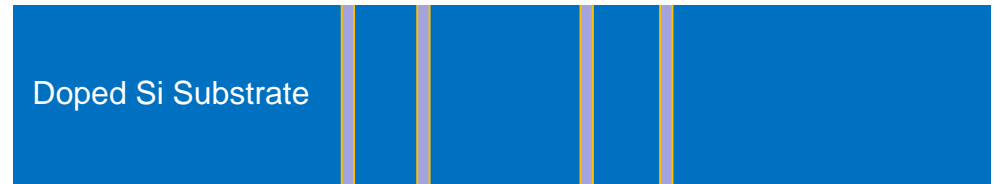
- Substrate with TSV

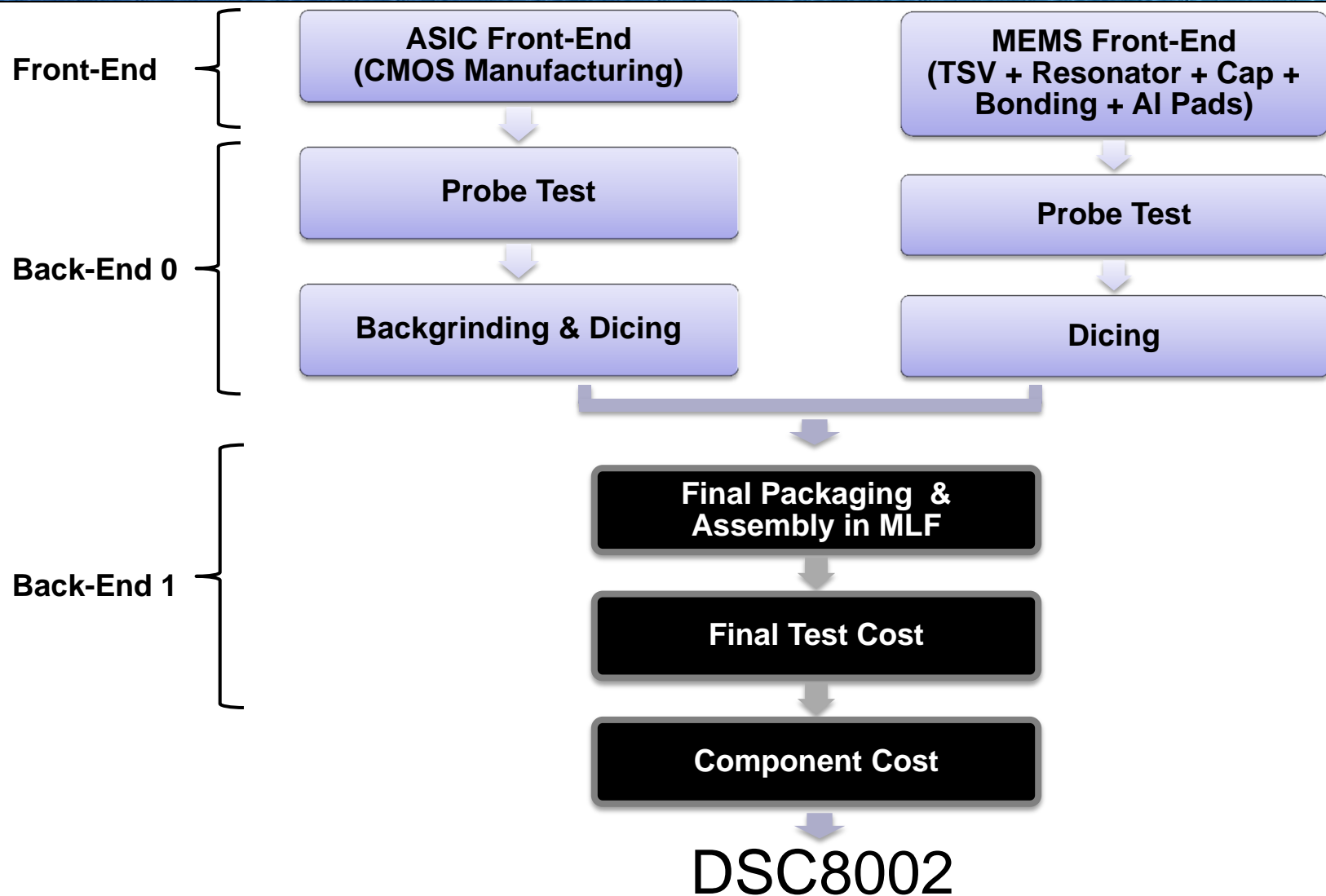


- Isolation (SiO₂+SiN)



- Polysilicon 1 (Deposition + Pattern)

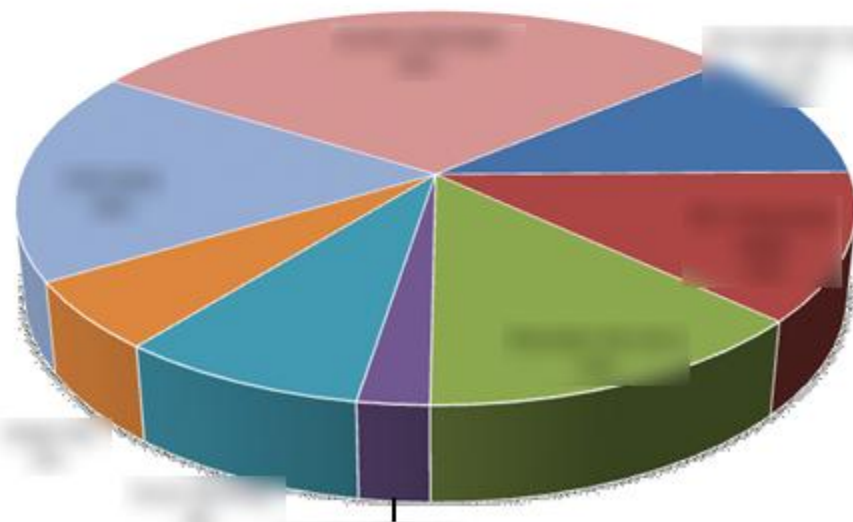




- We perform the economic analysis of the ASIC with the [IC Price+](#) software.
- We perform the economic analysis of the MEMS and the packaging with the [MEMS CoSim+](#) software.

MEMS Front-End	Low Yield		Medium Yield		High Yield	
	Cost	Breakdown	Cost	Breakdown	Cost	Breakdown
Raw Substrate Cost (2 x Si)						
TSV in Resonator Wafer						
Resonator Structure						
Cap Manufacturing						
Fusion Bonding						
Metal Pad						
Yield losses						
MEMS Front-End Cost						
Foundry Overhead						
MEMS Unprobed Wafer Cost						

MEMS Unprobed Wafer Cost Breakdown (Middle Yield)



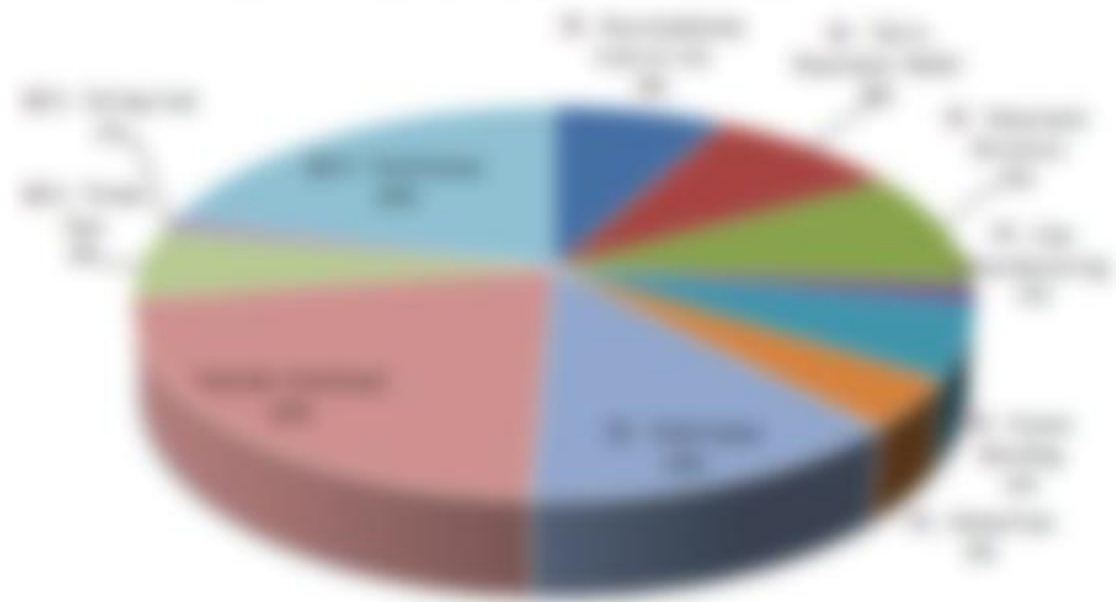
- The manufacturing of the **Raw Substrate Cost (2 x Si)** represents the main part of the front-end manufacturing cost with **25%**.

	Low Yield		Medium Yield		High Yield	
	Cost	Breakdown	Cost	Breakdown	Cost	Breakdown
Front-End Cost	10000	10000	10000	10000	10000	10000
BE 0 : Probe Test Cost	1000	1000	1000	1000	1000	1000
BE 0 : Dicing Cost	1000	1000	1000	1000	1000	1000
MEMS Wafer Cost	12000	12000	12000	12000	12000	12000
Nb of potential dies per wafer	1000	1000	1000	1000	1000	1000
Nb of good dies per wafer	1000	1000	1000	1000	1000	1000
Front-End Cost	10000	10000	10000	10000	10000	10000
BE 0 : Probe Test	1000	1000	1000	1000	1000	1000
BE 0 : Dicing Cost	1000	1000	1000	1000	1000	1000
BE 0 : Yield losses	1000	1000	1000	1000	1000	1000
MEMS Die Cost	14000	14000	14000	14000	14000	14000

- The **MEMS die cost** ranges from **12000** to **14000** according to yield variations.
- The **Front-end cost** (raw Si substrates, wafer processing and yield losses) represents around **71%** of the die cost.
- The **Back-End 0 cost** (Probe test, dicing and yield losses) represents **29%** of the die cost.

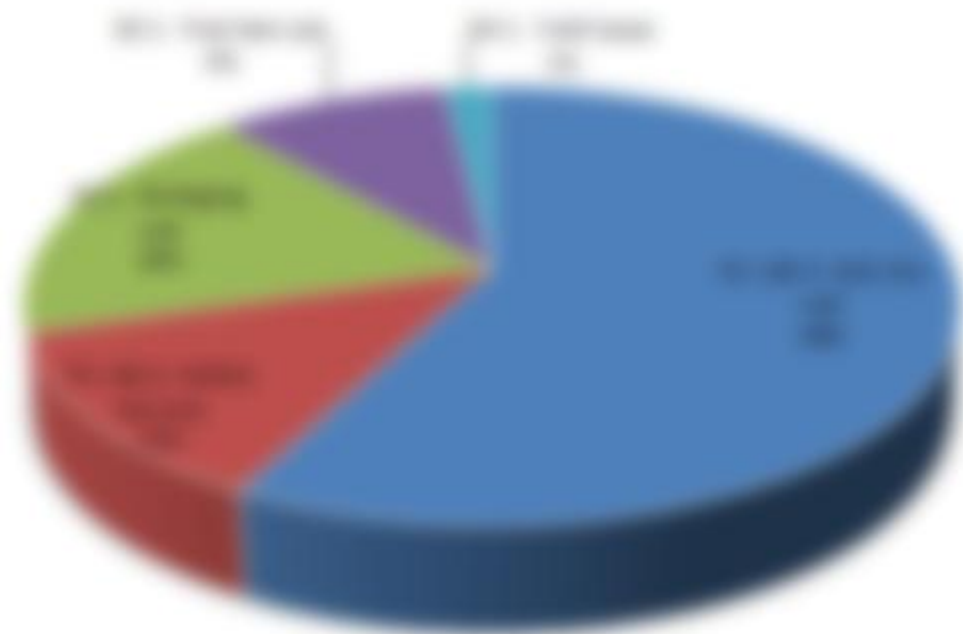
	Low Yield		Medium Yield		High Yield	
	Cost	Breakdown	Cost	Breakdown	Cost	Breakdown
FE : Raw Substrate Cost (2 x Si)						
FE : TSV in Resonator Wafer						
FE : Resonator Structure						
FE : Cap Manufacturing						
FE : Fusion Bonding						
FE : Metal Pad						
FE : Yield losses						
Foundry Overhead						
BE 0 : Probe Test						
BE 0 : Dicing Cost						
BE 0 : Yield losses						
MEMS Die Cost						

MEMS Die Cost Breakdown (Medium Yield)



	Low Yield		Medium Yield		High Yield	
	Cost	Breakdown	Cost	Breakdown	Cost	Breakdown
FE + BE 0 : ASIC Die cost	0.0000	0.0000	0.0000	0.0000	0.0000	0.0000
FE + BE 0 : MEMS Die Cost	0.0000	0.0000	0.0000	0.0000	0.0000	0.0000
BE 1 : Packaging cost	0.0000	0.0000	0.0000	0.0000	0.0000	0.0000
BE 1 : Final test cost	0.0000	0.0000	0.0000	0.0000	0.0000	0.0000
BE 1 : Yield losses	0.0000	0.0000	0.0000	0.0000	0.0000	0.0000
DSC8002 Component Cost	0.0000	0.0000	0.0000	0.0000	0.0000	0.0000

DSC8002 Component Cost Breakdown (Medium Yields)



- The component cost is between [redacted] according to yield variations.
- The die (ASIC + MEMS) represents [redacted] of the total manufacturing cost.
- The packaging cost represents [redacted] of the total manufacturing cost.
- Final test cost and yield losses (due to packaging and final test) represent [redacted] of the total manufacturing cost.